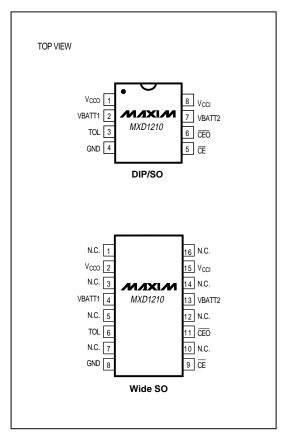
General Description

The MXD1210 nonvolatile RAM controller is a very lowpower CMOS circuit that converts standard (volatile) CMOS RAM into nonvolatile memory. It also continually monitors the power supply to provide RAM write protection when power to the RAM is in a marginal (out-oftolerance) condition. When the power supply begins to fail, the RAM is write protected, and the device switches to battery-backup mode.

_Applications

µP Systems Computers

Embedded Systems



Pin Configurations

Features

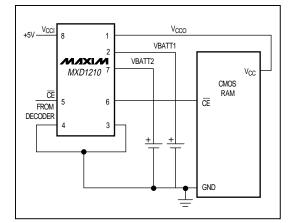
- Battery Backup
- Memory Write Protection
- ♦ 230µA Operating-Mode Quiescent Current
- 2nA Backup-Mode Quiescent Current
- Battery Freshness Seal
- Optional Redundant Battery
- Low Forward-Voltage Drop on V_{CC} Supply Switch
- ♦ 5% or 10% Power-Fail Detection Options
- Tests Battery Condition During Power-Up
- 8-Pin SO Available

Ordering Information

PART	TEMP. RANGE	PIN-PACKAGE
MXD1210CPA	0°C to +70°C	8 Plastic DIP
MXD1210CSA	0°C to +70°C	8 SO
MXD1210CWE	0°C to +70°C	16 Wide SO
MXD1210C/D	0°C to +70°C	Dice*
MXD1210EPA	-40°C to +85°C	8 Plastic DIP
MXD1210ESA	-40°C to +85°C	8 SO
MXD1210EWE	-40°C to +85°C	16 Wide SO
MXD1210MJA	-55°C to +125°C	8 CERDIP

*Contact factory for dice specifications.

__Typical Operating Circuit



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ABSOLUTE MAXIMUM RATINGS

V _{CCI} to GND0.3V, +7\	/
VBATT1 to GND0.3V, +7\	/
VBATT2 to GND0.3V, +7\	/
V _{CCO} to GND0.3V, V _S + 0.3V	/
(V _S = greater of V _{CCI} , VBATT1, VBATT2)
Digital Input and Output Voltages to GND 0.3V, V_{CCI} + 0.3V	/

Continuous Power Dissipation (T _A = +70°C) 8-Pin Plastic DIP (derate 9.09mW/°C above +70°C)727mW 8-Pin SO (derate 5.88mW/°C above +70°C)471mW 16-Pin Wide SO (derate 9.52mW/°C above +70°C)762mW 8-Pin CERDIP (derate 8.00mW/°C above +70°C)640mW
Operating Temperature Ranges
MXD1210C0°C to +70°C
MXD1210E40°C to +85°C
MXD1210MJA55°C to +125°C
Storage Temperature Range65°C to +150°C
Lead Temperature (soldering, 10sec) +300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

(T_A = T_{MIN} to T_{MAX}, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	
RECOMMENDED OPERATING CONDITIONS							
Supply Voltage	Vcci	TOL = GND	4.75		5.50	V	
		TOL = V _{CCO}	4.50		5.50		
Input High Voltage	Vih		2.2			V	
Input Low Voltage	VIL				0.8	V	
Battery Voltage (Note 1)	VBATT1 VBATT2	1 or 2 batteries	2.0		4.0	V	

ELECTRICAL CHARACTERISTICS

(V_{CCI} = +4.75V to +5.5V, TOL = GND; or V_{CCI} = +4.5V to +5.5V, TOL = V_{CCO}; T_A = T_{MIN} to T_{MAX}; unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS		MIN	ТҮР	MAX	UNITS
NORMAL SUPPLY MODE, TOL =	Vcco	4					
Supply Current	ICCI	V _{CCO} , CEO open, VBATT1 = VBATT2 = 3V		(0.23	0.5	mA
			MXD1210C	V _{CCI} - 0.20			
Output Supply Voltage	Vcco	ICCO1 = 80mA (Note 2)	MXD1210E	Vcci - 0.21			V
		(11010 2)	MXD1210M	V _{CCI} - 0.25			
			MXD1210C			80	
Output Supply Current	Icco	$V_{CCI} - V_{CCO} \le 0.2V$ (Note 2)	MXD1210E	(0.23	75	mA
			MXD1210M	(0.23	65	
Input Leakage Current	ΙL					±1.0	μA
Output Leakage Current	lol					±1.0	μA
High-Level Output Voltage	VOH	I _{OH} = -1mA		2.4			V
Low-Level Output Voltage	V _{OL}	I _{OL} = 4mA				0.4	V
		TOL = GND		4.50		4.74	V
V _{CCI} Trip Point	VCCTP	TOL = V _{CCO}		4.25		4.49	v

2

MIXI**M**

ELECTRICAL CHARACTERISTICS

(V_{CCI} < VBATT; positive edge rate at VBATT1, VBATT2 > $0.1V/\mu$ s, T_A = T_{MIN} to T_{MAX}; unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS		MIN	ΤΥΡ	MAX	UNITS
BATTERY-BACKUP MODE							
Quiescent Current (Note 1)	la vert	V _{CCO} , <u>CEO</u> open	MXD1210C/E		2	100	nA
	IBATT	VCCI = 0V	MXD1210M			5	μA
Output Supply Current (Notes 3, 4)	ICCO2	VBATT - V _{CCO} ≤ 0.2V				300	μA
CEO Output Voltage	Vo	Output open		VBATT - 0	.2		V

ELECTRICAL CHARACTERISTICS

 $(T_A = T_{MIN} \text{ to } T_{MAX}, \text{ unless otherwise noted.})$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
INPUT/OUTPUT CAPACITANCE (M	lote 5)					
Input Capacitance	CIN				5	pF
Output Capacitance	C _{OUT}				7	pF

 $V_{CC} POWER TIMING CHARACTERISTICS$ $(V_{CCI} = +4.75V \text{ to } +5.5V, \text{ TOL} = \text{GND; or } V_{CCI} = +4.5V \text{ to } +5.5V, \text{ TOL} = V_{CCO}; T_A = T_{MIN} \text{ to } T_{MAX}; \text{ unless otherwise noted.})$

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
		D (1) 0	MXD1210C	5	10	20	
CE Propagation Delay tPD	tPD	$R_L = 1k\Omega,$ $C_L = 50pF$	MXD1210E	5	10	22	ns
			MXD1210M	5	10	25]
CE High to Power-Fail (Note 5)	tPF				0		ns

TIMING CHARACTERISTICS

 $(V_{CCI} < +4.75V$ to +5.5V, TOL = GND; or $V_{CCI} < +4.5V$, TOL = V_{CCO} ; T_A = T_{MIN} to T_{MAX}; unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Recovery at Power-Up	tREC		2	5	20	ms
V _{CC} Slew-Rate Power-Down	tF	To out-of-tolerance condition	300			
VCC Siew-Rale Fower-Down	tFB	Tolerance to battery power	10			μs
V _{CC} Slew-Rate Power-Up	tR		0			μs
CE Pulse Width (Note 6)	tCE				1.5	μs

Note 1: Only one battery input is required. Unused battery inputs must be grounded.

Note 2: ICCO1 is the maximum average load current the MXD1210 can supply to the memories.

Note 3: ICCO2 is the maximum average load current the MXD1210 can supply to the memories in battery-backup mode.

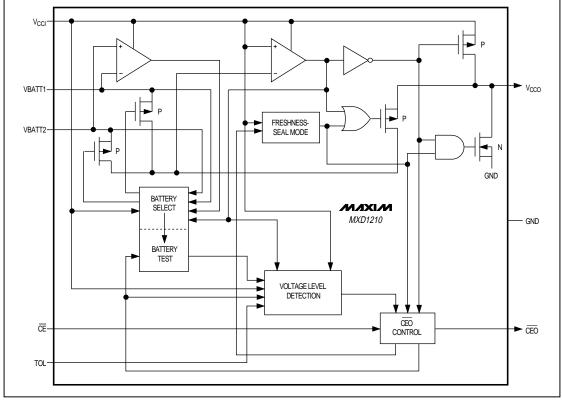
Note 4: CEO can sustain leakage current only in battery-backup mode.

Note 5: Guaranteed by design.

Note 6: tCE max must be met to ensure data integrity on power loss.

MXD1210

			Pin Description
	PIN	NAME	FUNCTION
8-PIN DIP/SO	16-PIN WIDE SO		FUNCTION
1	2	Vcco	Backed-up supply to RAM
2	4	VBATT1	Battery 1 positive connection
3	6	TOL	Tolerance select pin
4	8	GND	Ground
5	9	CE	Chip-enable input
6	11	CEO	Chip-enable output
7	13	VBATT2	Battery 2 positive connection
8	15	Vcci	5V power supply to chip
-	1, 3, 5, 7 10, 12, 14, 16	N.C.	No connect, not internally connected







M/X/M

Detailed Description

Main Functions

The MXD1210 executes five main functions to perform reliable RAM operation and battery backup (see *Typical Operating Circuit* and Figure 1):

- RAM Power-Supply Switch: The switch directs power to the RAM from the incoming supply or from the selected battery, whichever is at the greater voltage. The switch control uses the same criterion to direct power to MXD1210 internal circuitry.
- Power-Failure Detection: The write-protection function is enabled when a power failure is detected. The power-failure detection range depends on the state of the TOL pin as follows:

CONDITION	V _{CCTP} RANGE (V)
TOL = GND	4.75 to 4.50
TOL = VCCO	4.50 to 4.25

Power-failure detection is independent of the batterybackup function and precedes it sequentially as the power-supply voltage drops during a typical power failure.

- 3. Write Protection: This holds the chip-enable output $\overline{(CEO)}$ to within 0.2V of V_{CCI} or of the selected battery, whichever is greater. If the chip-enable input $\overline{(CE)}$ is low (active) when power failure is detected, then CEO is held low until CE is brought high, at which time \overline{CEO} is gated high for the duration of the power failure. The preceding sequence completes the current RD/WR cycle, preventing data corruption if the RAM access is a WR cycle.
- 4. Battery Redundancy: A second battery is optional. When two batteries are connected, the stronger battery is selected to provide RAM backup and to power the MXD1210. The battery-selection circuitry remains active while in the battery-backup mode, selecting the stronger battery and isolating the weaker one. The battery-selection activity is transparent to the user and the system. If only one battery is connected, the second battery input should be grounded.

5. Battery-Status Warning: This notifies the system when the stronger of the two batteries measures ≤ 2.0V. Each time the MXD1210 is repowered (V_{CCI} > V_{CCTP}) after detecting a power failure, the battery voltage is measured. If the battery in use is low, following the MXD1210 recovery period, the device issues a warning to the system by inhibiting the second memory cycle. The sequence is as follows:

First access: read memory location n, loc(n) = x

Second access: write memory location n,

loc(n) = complement(x)

Third access: read memory location n, loc (n) = ?

If the third access (read) is complement (x), then the battery is good; otherwise, the battery is not good. Return to loc(n) = x following the test sequence.

Freshness-Seal Mode

MXD1210

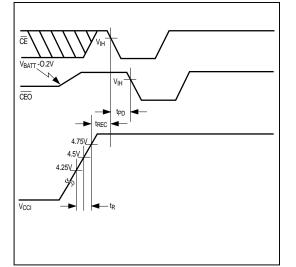
The freshness-seal mode relates to battery longevity during storage rather than directly to battery backup. This mode is activated when the first battery is connected, and is defeated when the voltage at V_{CCI} first exceeds V_{CCTP}. In the freshness-seal mode, both batteries are isolated from the system; that is, no current is drained from either battery, and the RAM is not powered by either battery. This means that batteries can be installed and the system can be held in inventory without battery discharge. The positive edge rate at VBATT1 and VBATT2 should exceed 0.1V/ μ s. The batteries will maintain their full shelf-life while installed in the system.

Battery Backup

The *Typical Operating Circuit* shows the MXD1210 connected in order to write protect the RAM when V_{CC} is less than 4.75V, and to provide battery backup to the supply.

M/IXI/M





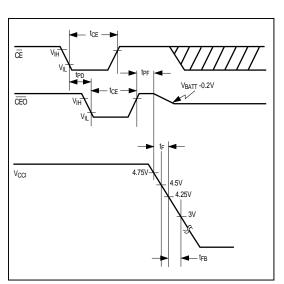
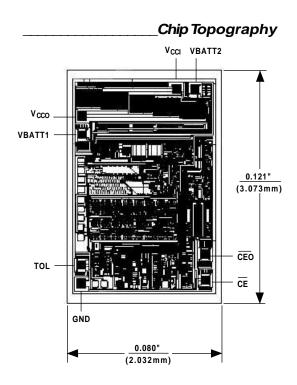


Figure 2. Power-Up Timing Diagram

Figure 3. Power-Down Timing Diagram

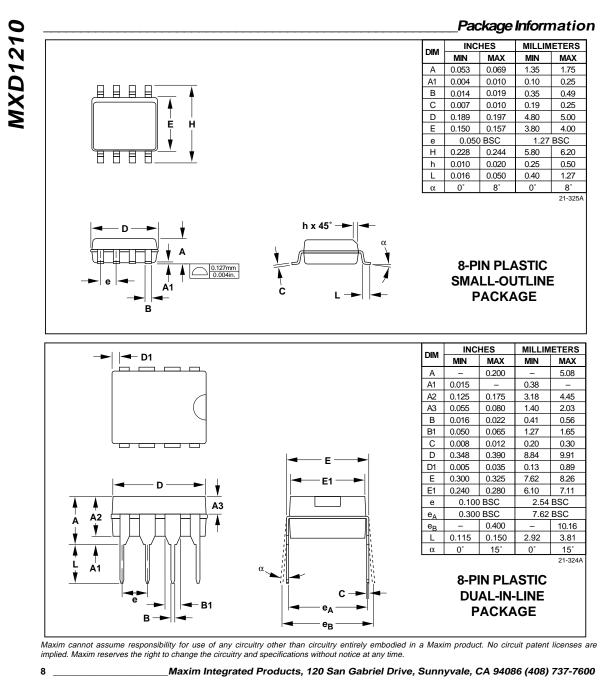
M/X/M



MXD1210

TRANSISTOR COUNT: 1436; LEAVE SUBSTRATE UNCONNECTED.

WIXIW



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